- 1 1. A method comprising:
- 2 forming a phase change material over a heater in
- 3 a pore formed in an insulator so that a first portion of
- 4 said material extends over said insulator and a second
- 5 portion of said material extends into said pore.
- 1 2. The method of claim 1 including forming a pore in
- 2 the insulator over a semiconductor substrate.
- 1 3. The method of claim 2 including completely
- 2 filling said pore with a metal to form a heater.
- 1 4. The method of claim 3 including planarizing the
- 2 upper surface of said insulator.
- 1 5. The method of claim 3 including removing an upper
- 2 portion of said metal in said pore.
- 1 6. The method of claim 5 including depositing a
- 2 phase change material into said pore and over said
- 3 insulator.
- 1 7. The method of claim 6 including patterning and
- 2 etching said phase change material over said insulator.

- 1 8. The method of claim 7 including forming a T-
- 2 shaped phase change material.
- 1 9. The method of claim 3 including forming a
- 2 sidewall spacer in said pore.
- 1 10. The method of claim 9 including depositing metal
- 2 in said pore after forming said sidewall spacer.
- 1 11. A apparatus comprising:
- an insulator having a pore formed in said
- 3 insulator;
- a heater formed in said pore; and
- 5 a phase change material over said insulator and
- 6 extending into said pore.
- 1 12. The apparatus of claim 11 wherein said phase
- 2 change material is arranged in said pore to reduce the
- 3 occurrence of parasitic conductive paths.
- 1 13. The apparatus of claim 11 wherein said phase
- 2 change material is T-shaped.
- 1 14. The apparatus of claim 11 including a sidewall
- 2 spacer in said pore.

- 1 15. The apparatus of claim 11 wherein said pore is
- 2 substantially filled by said heater.
- 1 16. The apparatus of claim 11 wherein said heater is
- 2 metallic.
- 1 17. The apparatus of claim 11 including an electrode
- 2 over said phase change material.
- 1 18. The apparatus of claim 11 wherein said phase
- 2 change material is an ovonic material.
- 1 19. The apparatus of claim 11 wherein said phase
- 2 change material is a chalcogenide.
- 1 20. The apparatus of claim 11 wherein the entire
- 2 upper extent of said pore is filled with said phase change
- 3 material.
- 1 21. A system comprising:
- 2 a processor-based device;
- a wireless interface coupled to said processor-
- 4 based device; and
- 5 a semiconductor memory coupled to said device,
- 6 said memory including an insulator having a pore formed in
- 7 said insulator, a heater formed in said pore, and a phase

- 8 change material over said insulator and extending into said
- 9 pore.
- 1 22. The system of claim 21 wherein said wireless
- 2 interface includes a dipole antenna.
- 1 23. The system of claim 21 wherein said phase change
- 2 material is T-shaped.
- 1 24. The system of claim 21 wherein said phase change
- 2 material is arranged to reduce the occurrence of parasitic
- 3 conductive paths.
- 1 25. The system of claim 21 wherein said phase change
- 2 material is arranged in the upper extent of said pore to
- 3 prevent the occurrence of a parasitic conductive path
- 4 through said pore past said phase change material.
- 1 26. The system of claim 21 wherein said phase change
- 2 material is an ovonic material.
- 1 27. The system of claim 21 wherein said phase change
- 2 material is a chalcogenide.
- 1 28. The system of claim 21 including a sidewall
- 2 spacer in said pore.

- 1 29. The system of claim 21 wherein said heater
- 2 substantially fills said pore.
- 1 30. The system of claim 21 wherein said heater is
- 2 metallic.
- 1 31. The system of claim 21 including an electrode
- 2 over said phase change material.